





In this paper, we present a survey of existing approaches on persistent naming in parametric system. We identify five common concepts that may be found in most of the studies. We propose two orthogonal criteria for classifying persistent naming approaches. This survey is intended to represent a state of the art of robust parametric reevaluation of geometric models.

**8** A design/constraint model to capture design intent Chia-Hui Shih, Bill AndersonMay 1997 **Proceedings of the fourth ACM symposium on Solid modeling and applications**

Publisher: ACM Press

Full text available:  pdf(1.06 MB) Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)**9** A constraint-based manipulator toolset for editing 3D objects C. Hsu, G. Alt, Z. Huang, E. Beier, B. BrüderlinMay 1997 **Proceedings of the fourth ACM symposium on Solid modeling and applications**

Publisher: ACM Press

Full text available:  pdf(1.71 MB) Additional Information: [full citation](#), [references](#), [index terms](#)**10** Geometric modeling: a new fundamental framework and its practical implications Ari RappoportDecember 1995 **Proceedings of the third ACM symposium on Solid modeling and applications**

Publisher: ACM Press

Full text available:  pdf(1.20 MB) Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)**11** A relational model for interactive manipulation of form features based on algebraic geometry G. Brunetti, T. De Martino, B. Falcidieno, S. HabingerDecember 1995 **Proceedings of the third ACM symposium on Solid modeling and applications**

Publisher: ACM Press

Full text available:  pdf(891.45 KB) Additional Information: [full citation](#), [references](#), [citations](#), [index terms](#)

**Keywords:** algebraic geometry, design by features, geometric constraints, integrated feature-based systems, interactive feature manipulation, user-defined features

Results 1 - 11 of 11

The ACM Portal is published by the Association for Computing Machinery. Copyright © 2006 ACM, Inc.

[Terms of Usage](#) [Privacy Policy](#) [Code of Ethics](#) [Contact Us](#)Useful downloads:  [Adobe Acrobat](#)  [QuickTime](#)  [Windows Media Player](#)  [Real Player](#)



Welcome United States Patent and Trademark Office

## Search Results

## BROWSE

## SEARCH

## IEEE XPLORE GUIDE

## SUPPORT

Results for "(['computer aided design' and 'design intent')&lt;in&gt;metadata)"

Your search matched 2 of 1325881 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

e-mail printer friendly

## » Search Options

[View Session History](#)[New Search](#)

## Modify Search

**Search** >
☐ Check to search only within this results set

 Display Format: ☒ Citation ☐ Citation & Abstract

## » Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

[view selected items](#)[Select All](#) [Deselect All](#)

- ☐ 1. **Relational computer-aided design**  
 Hanna, J.R.P.; Millar, R.J.; Frazer, J.H.;  
Design Systems with Users in Mind: The Role of Cognitive Artefacts, IEE Colloquium on  
 6 Dec 1995 Page(s):3/1 - 3/3  
[AbstractPlus](#) | Full Text: [PDF](#)(236 KB) IEE CNF
2. **Design Intent Coverage - A New Paradigm for Formal Property Verification**  
 Basu Prasenjit ; Das Sayantan ;  
IEEE Transactions on Computer-Aided Design of Integrated Circuits and Systems : Accepted for  
future publication  
 Volume PP, Issue 99, 2005 Page(s):1 - 1  
 Digital Object Identifier 10.1109/TCAD.2005.859490  
[AbstractPlus](#) | Full Text: [PDF](#)(208 KB) IEEE JNL

[Help](#) [Contact Us](#) [Privacy & Security](#) [IEEE.org](#)

© Copyright 2006 IEEE - All Rights Reserved

 Indexed by  
 Inspec



Welcome United States Patent and Trademark Office

## Search Results

## BROWSE

## SEARCH

## IEEE XPLORE GUIDE

## SUPPORT

Results for "(['computer aided design' and 'parametric design' )&lt;in&gt;metadata)"

Your search matched 2 of 1325881 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

[e-mail](#) [printer friendly](#)

## » Search Options

[View Session History](#)[New Search](#)

## Modify Search

(['computer aided design' and 'parametric design' )&lt;in&gt;metadata)

[Search](#) >☐ Check to search only within this results setDisplay Format: ☒ Citation ☐ Citation & Abstract

## » Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

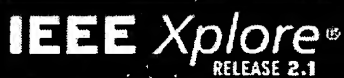
IEEE STD IEEE Standard

[view selected items](#) [Select All](#) [Deselect All](#)

- ☐ 1. **Reliability-directed computer-aided design system**  
 Abramov, O.V.; Katueva, Y.V.; Lazarev, G.I.; Suponya, A.A.;  
Computer Aided Control System Design, 1999. Proceedings of the 1999 IEEE International Symposium on  
 22-27 Aug. 1999 Page(s):375 - 379  
 Digital Object Identifier 10.1109/CACSD.1999.808677  
[AbstractPlus](#) | Full Text: [PDF](#)(404 KB) IEEE CNF  
[Rights and Permissions](#)
- ☐ 2. **A topological entity matching technique for geometric parametric models**  
 Agbodan, D.; Marcheix, D.; Pierra, G.; Thabaud, C.;  
Shape Modeling International, 2003  
 12-15 May 2003 Page(s):235 - 244  
 Digital Object Identifier 10.1109/SMI.2003.1199623  
[AbstractPlus](#) | Full Text: [PDF](#)(1086 KB) IEEE CNF  
[Rights and Permissions](#)

 indexed by  
[Help](#) [Contact Us](#) [Privacy & Security](#) [IEEE.org](#)

© Copyright 2006 IEEE – All Rights Reserved



Welcome United States Patent and Trademark Office

**Search Results****BROWSE****SEARCH****IEEE XPLORE GUIDE****SUPPORT**

Results for " (('computer aided design' and 'parametric design' and 'design intent')&lt;in&gt;metadata)"

Your search matched 0 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

e-mail printer friendly

## » Search Options

[View Session History](#)[New Search](#)

## Modify Search

(('computer aided design' and 'parametric design' and 'design intent')&lt;in&gt;metadata)

**Search** >☐ Check to search only within this results setDisplay Format: ☒ Citation ☐ Citation & Abstract

## » Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

**No results were found.**

Please edit your search criteria and try again. Refer to the Help pages if you need assistance revising your search.

[Help](#) [Contact Us](#) [Privacy & Security](#) [IEEE.org](#)

© Copyright 2006 IEEE – All Rights Reserved

